

FACULTY HIGHLIGHT

faculty highlight



PRISM faculty member F. Duncan Haldane receives Nobel Prize in Physics

NEWS

NEW PRISM IAC & MNFL FACILITIES INAUGURATION

OCTOBER 26 | **REGISTRATION REQUIRED**



Please join us for the inauguration of PRISM's new state-of-the-art IAC and MNFL facilities. With more than double the space, upgraded equipment, and expanded staff, PRISM's new facilities are premier locations for materials characterization and fabrication. Come hear presentations by faculty and applications experts, tour instrumentation demos and 'thrill rides', and attend poster and networking sessions. Discover the new capabilities and resources we have to offer that will take your research to the next level.



PRISM annual blacksmithing and metallurgy event | see photos

CALL FOR PROPOSALS

proposals

The Eric and Wendy Schmidt Transformative Technology Fund— to fund risk-taking projects, understanding that with risk comes not only the potential for huge reward, but some frequency of failure. [READ MORE](#)
Deadline: Thursday, October 20, 2016, 5:00 PM

2017 NSF Major Research Instrumentation (MRI) — to encourage the development and acquisition of research instrumentation for shared inter-and/or intraorganizational use and in concert with private sector partners. Proposals may be for a single instrument, a large system of instruments, or multiple instruments that share a common or specific research focus. [READ MORE](#)
Deadline: Monday, October 24, 2016, 5:00 PM

FOR ASSISTANCE IN SUBMITTING THESE OR ANY OTHER PROPOSALS, PLEASE CONTACT NANCY YOUNG (8-2553 or nancyy@princeton.edu)

PRISM | PCCM SEMINAR SERIES

October 19

Chris Bowman
University of Colorado

November 9

Shelby Nelson
Eastman Kodak

November 16

Raffi Budakian
University of Illinois

For a complete schedule, go to
www.princeton.edu/prism

NEW EQUIPMENT IN THE IAC

ThermoFisher K-Alpha+ X-Ray Photoelectron Spectrometer (XPS)

The ThermoFisher K-Alpha X-Ray Photoelectron Spectrometer (XPS) is now available for usage in the **Imaging and Analysis Center**. This new instrument provides quantitative elemental, chemical state and functional group information from the surface of materials (top ~1-10nm). With a built-in ion beam the sample surface can be gently mill away for depth-profile analysis. This system is equipped with:

- a 180° double focusing hemispherical analyzer with 128-channel detector
- Al K α micro-focused monochromator with variable X-ray spot size (30-400 μm in 5 μm steps)
- Ar+ beam energy range of 30-4000 eV
- 4-axis sample stage
- vacuum transfer module

